Ref #	Hits	Hits Search Query		Default Operator	Plurals	Time Stamp	
<b>L1</b>	16	"5692181".pn. or "5767854".pn. or "5926818".pn. or "5940818". pn. or "5943668" pn. or "5943677".pn. or "5978796".pn. or "5999192".pn.	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 11:06	
L2	4	1 and (metadata or "meta-data")	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:42	
L3	41	"5978796"	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 11:10	
L4	23	3 and (metadata or "meta-data")	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 11:11	
L5	7	4 and schema\$1	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:41	
L6	0	5 and (metadata or "meta-data") same dimension\$1 same measures	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:53	
נס.	0	5 and (metadata or "meta-data") same dimension\$1 same measure\$1	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:10	
L8	0	5 and (metadata or "meta-data") same technical	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:53	
L9	2	5 and (metadata or "meta-data") same (access\$3 or measure\$1)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:54	
L10	2	5 and (metadata or "meta-data") same (access\$3)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:54	
L11	O	5 and (metadata or "meta-data") same (measure\$1)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:54	
L12	4	5 and (metadata or "meta-data") same (dimension\$1)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 13:48	
L13	0	10 and 12	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 12:54	
L14	14363	"707"/.ccls.	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 13:49	
L15	7	14 and (map\$5 or link\$3) same dimension\$1 same measures same (metadata or "meta-data")	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 13:50	

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L16	7	14 and (map\$5 or link\$3) same dimension\$1 same measures same (metadata or "meta-data" same schema\$1)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 13:50
L17	2	14 and (map\$5 or link\$3) same dimension\$1 same measures same (metadata or "meta-data") same schema\$1	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 14:22
L18	45	14 and (map\$5 or link\$3) same (metadata or "meta-data") same schema\$1	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 14:22
L19	4	14 and ((map\$5 or link\$3) same (metadata or "meta-data") same schema\$1)[ab]	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 15:44
L20	14363	14	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 15:23
L21	25	14 and ((map\$5 or link\$3) same (metadata or "meta-data") same schema\$1 same database)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 15:45
L22	22	21 not 19	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 16:02
L23	2	((map\$4 or link\$3) same (metadata or "meta-data") same schema)[clm]	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 16:04
L24	41	705/1.ccls. and model same (map\$4)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:11
L25	58	705/1.ccls, and model same (map\$4 or search\$3)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:11
L26	13	705/1.ccls. and model same (map\$4 or search\$3) same database	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:13
L27	4	26 and schema\$1	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:20
L28	110	(metadatabase or meta adj database or "meta-database")	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:21
L29	44	(metadatabase or meta adj database or "meta-database") and (schema\$3)	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:21
L30	26	(metadatabase or meta adj database or "meta-database") and (schema\$3 and (analy\$4 or search\$3))	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:22

L31	11	(metadatabase or meta adj database or "meta-database") and (schema\$3 and (analy\$4 or search\$3)) and model\$1	USPAT; EPO; DERWENT	OR	OFF	2005/02/28 17:23
L32	11	(metadatabase or meta adj	USPAT;	OR	OFF	2005/02/28 17:23
		database or "meta-database") and	EPO;			
		(schema\$3 and (analy\$4 or	DERWENT			
		search\$3)) and model\$1 and				
		(manager\$1 or maintain\$4)				

High Performance Distributed Computing, 2001. Proceedings. 10th IEEE International Symposium on , 7-9 Aug. 2001 Pages: 228 - 238

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5 A metadata system for information modeling and integration Hsu, C.; Bouziane, M.; Cheung, W.; Nogues, J.; Rattner, L.; Yee, L.; Systems Integration, 1990. Systems Integration '90., Proceedings of the First International Conference on , 23-26 April 1990 Pages:616 - 624

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# A metadata system for information modeling and integration

Hsu, C. Bouziane, M. Cheung, W. Nogues, J. Rattner, L. Yee, L.

Rensselaer Polytech. Inst., Troy, NY, USA;

This paper appears in: Systems Integration, 1990. Systems Integration Proceedings of the First International Conference on

Meeting Date: 04/23/1990 - 04/26/1990 Publication Date: 23-26 April 1990 Location: Morristown, NJ USA

On page(s): 616 - 624 Reference Cited: 10

Inspec Accession Number: 3864095

# Abstract:

Information integration in computerized enterprises entails global modeling at repository systems that represent both data resources and control knowledge enterprise. Toward this end, a metadata system has been developed based c stage entity-relationship approach. The system's functions include creation of models, structural models, and implementation schemata for both data and k The mappings between functional and structural models, as well as between s models and implementation schemata, are automated. Integration of heterog subsystem models across the enterprise is another function of the system. Th global conceptual model of the enterprise could be used for administration pu further mapped into physical schema for implementation. Management of th metadata repository is a third function. The system supports the creation, st management of the metadatabase as a stand-alone global information resour dictionary for all enterprise users. The creation and population of the metadat fully automated according to the information model. Manipulation and query a metadatabase are done through a metadata engine, which is implemented u relational database management system coupled with a Lisp environment

#### **Index Terms:**

management information systems relational databases Lisp environment administrat computerized enterprises conceptual model control knowledge data management c manipulation data resources functional models global modeling heterogeneous sub models implementation schemata information integration information modeling met system metadatabase physical schema queries relational database management s repository systems stand-alone global information resources dictionary structural mod stage entity-relationship approach

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